Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/808,389	KONISHI ET AL.	
Examiner	Art Unit	_
Brian Kunzer	2814	

			
	SEAR	CHED	
Class	Subclass	Date	Examiner
257	686, 777, 778, 728	9/1/2005	ВК
330	310, 311	8/31/2005	ВК
330	66,126	9/6/2005	ВК

	INTERFERENCE SEARCHED					
Subclass	Date	Examiner				
	Subclass	Subclass Date				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
257/686, 777, 778, 728 (text search only, see search history printout)	9/1/2005	вк		
330/66,126,310, 311, (text search only, see search history printout)	8/31/2005	вк		
EAST (USPAT, US-PGPUB, USOCR) - see search history printout	9/1/2005	вк		
INSPEC, Abs., multiple chip frequencies, 1969-present	8/31/2005	вк		